Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/787,668	DEHAAN ET AL.	
Examiner	Art Unit	
Tam M. Nguyen	1764	

SEARCHED					
Class	Subclass	Date	Examiner		
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	INTERFERENCE SEARCHED					
Subclass	Date	Examiner				
	Subclass	Subclass Date				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INTERFRENCE SEARCHED - SEE PGPUB PRINTOUT	10/30/2006	TN		
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